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## Fast Switching Emitter Controlled Diode





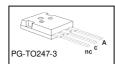




## Features:

- 600V EmCon technology
- Fast recovery
- Soft switching
- Low reverse recovery charge
- Low forward voltage
- 175°C junction operating temperature
- Easy paralleling
- Pb-free lead plating; RoHS compliant
- Complete product spectrum and PSpice Models: http://www.infineon.com/emcon/





## **Applications:**

- Welding
- Motor drives

Туре	$V_{RRM}$	I <sub>F</sub>	V <sub>F,Tj=25°C</sub>	$T_{\rm j,max}$	Marking	Package
IDW75E60	600V	75A	1.65V	175°C	D75E60	PG-TO247-3

#### **Maximum Ratings**

Parameter	Symbol	Value	Unit	
Repetitive peak reverse voltage	$V_{RRM}$	600	٧	
Continuous forward current				
$T_{\rm C} = 25^{\circ}{\rm C}$		120	A	
$T_{\rm C} = 90^{\circ}{\rm C}$	/ <sub>F</sub> 82			
$T_{\rm C}$ = 100°C		75		
Surge non repetitive forward current	,	220	^	
$T_{\rm C} = 25^{\circ}{\rm C}$ , $t_{\rm p} = 10$ ms, sine halfwave	I <sub>FSM</sub>	220	Α	
Maximum repetitive forward current	1	225	۸	
$T_{\rm C}$ = 25°C, $t_{\rm p}$ limited by $t_{\rm j,max}$ , $D$ = 0.5	I <sub>FRM</sub>	225	Α	
Power dissipation				
$T_{\rm C} = 25^{\circ}{\rm C}$	D	300	w	
$T_{\rm C} = 90^{\circ}{\rm C}$	$P_{tot}$	170	VV	
$T_{\rm C}=100^{\circ}{\rm C}$		150		
Operating junction temperature	T <sub>j</sub>	-40+175		
Storage temperature	$T_{ m stg}$	-55+150	°C	
Soldering temperature 1.6mm (0.063 in.) from case for 10 s	Ts	260		



Value

Unit



### **Thermal Resistance**

**Parameter** 

Parameter	Symbol	Conditions	Max. Value	Unit
Characteristic				
Thermal resistance,	$R_{thJC}$		0.5	K/W
junction – case				
Thermal resistance,	$R_{thJA}$		40	
junction – ambient				

## **Electrical Characteristic,** at $T_j = 25$ °C, unless otherwise specified

Symbol

raiametei	Syllibol	Conditions	min.	typ.	max.	Ullit
Static Characteristic						
Collector-emitter breakdown voltage	$V_{RRM}$	I <sub>R</sub> =0.25mA	600	-	-	٧
Diode forward voltage	$V_{F}$	I <sub>F</sub> =75A				
		<i>T</i> <sub>j</sub> =25°C	-	1.65	2.0	
		$T_j = 175^{\circ} \text{C}$	-	1.65	-	
Reverse leakage current	$I_{R}$	V <sub>R</sub> =600V				μА
		$T_{\rm j}$ =25°C	-	-	40	
		T <sub>j</sub> =175°C	-	-	2500	

**Conditions** 

## **Dynamic Electrical Characteristics**

Diode reverse recovery time	$t_{rr}$	$T_j=25$ °C	-	121	-	ns
Diode reverse recovery charge	$Q_{rr}$	$V_{R}$ =400V, $I_{F}$ =75A,	1	2.4	-	μC
Diode peak reverse recovery current	$I_{rr}$	$dI_F/dt=1460A/\mu s$	-	38.5	-	Α
Diode peak rate of fall of reverse recovery current during $t_{\rm b}$	dI <sub>rr</sub> /dt		-	921	-	A/μs

Diode reverse recovery time	$t_{rr}$	T <sub>j</sub> =125°C	-	155	-	ns
Diode reverse recovery charge	$Q_{rrm}$	$V_{R}$ =400V, $I_{F}$ =75A,	-	4.4	-	μC
Diode peak reverse recovery current	I <sub>rr</sub>	$dI_F/dt=1460A/\mu s$	-	46.6	-	Α
Diode peak rate of fall of reverse recovery current during $t_{\rm b}$	dI <sub>rr</sub> /dt		-	960	-	A/μs

Diode reverse recovery time	trr	T <sub>j</sub> =175°C	-	182	-	ns
Diode reverse recovery charge	$Q_{rrm}$	$V_{R}$ =400V, $I_{F}$ =75A,	-	5.8	-	μC
Diode peak reverse recovery current	$I_{rr}$	$dI_F/dt=1460A/\mu s$	-	56.2	-	Α
Diode peak rate of fall of reverse recovery current during $t_{\rm b}$	dI <sub>rr</sub> /dt		-	1013	-	A/μs



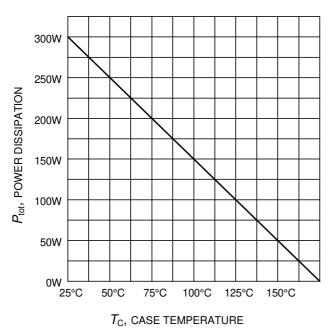
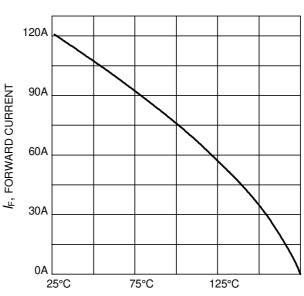


Figure 1. Power dissipation as a function of case temperature  $(T_i \le 175^{\circ}C)$ 



 $T_{\rm C}$ , CASE TEMPERATURE Figure 2. Diode forward current as a function of case temperature  $(T_{\rm i} \le 175^{\circ}{\rm C})$ 

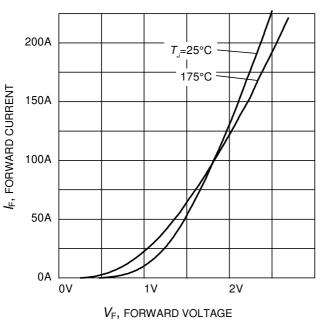
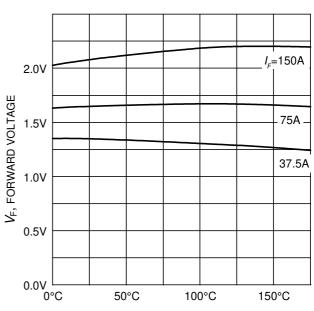


Figure 3. Typical diode forward current as a function of forward voltage



 $T_{\rm J}$ , JUNCTION TEMPERATURE Figure 4. Typical diode forward voltage as a function of junction temperature

 $T_1 = 25^{\circ}C$ 



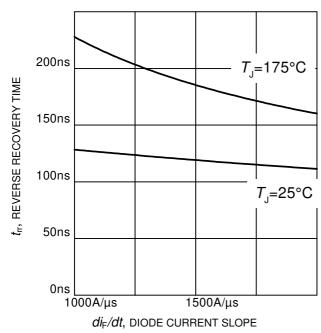
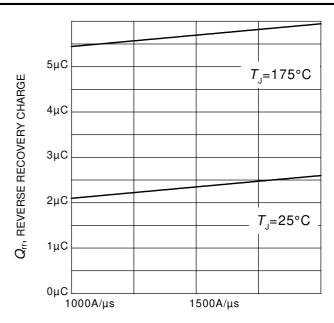
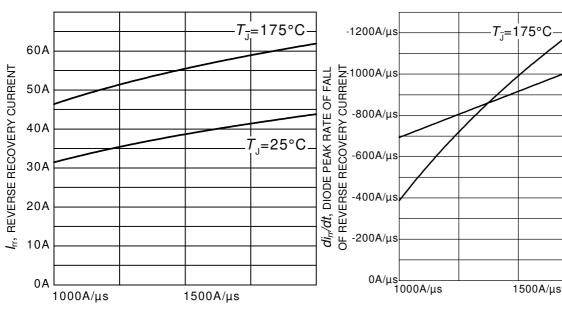


Figure 5. Typical reverse recovery time as a function of diode current slope  $(V_R=400\text{V}, I_F=75\text{A}, \text{Dynamic test circuit in Figure E})$ 



di<sub>F</sub>/dt, DIODE CURRENT SLOPE

Figure 6. Typical reverse recovery charge as a function of diode current slope  $(V_R = 400 \text{V}, I_F = 75 \text{A}, \text{Dynamic test circuit in Figure E})$ 



di<sub>F</sub>/dt, DIODE CURRENT SLOPE

Figure 7. Typical reverse recovery current as a function of diode current slope

( $V_R = 400V$ ,  $I_F = 75A$ , Dynamic test circuit in Figure E)  $di_{\rm F}/dt$ , DIODE CURRENT SLOPE

Figure 8. Typical diode peak rate of fall of reverse recovery current as a function of diode current slope ( $V_R$ =400V,  $I_F$ =75A, Dynamic test circuit in Figure E)



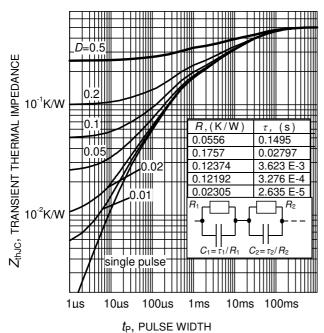
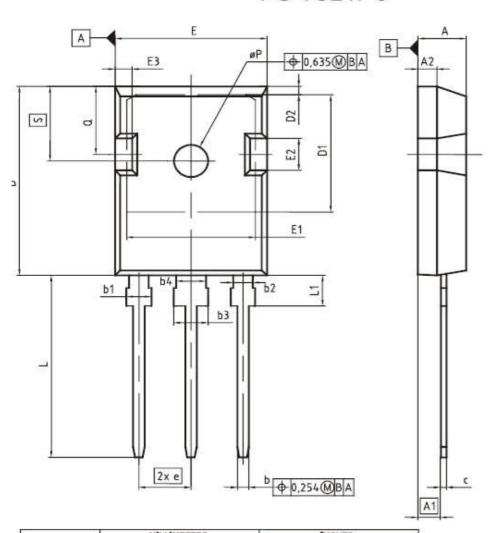


Figure 9. Diode transient thermal impedance as a function of pulse width  $(D=t_{\rm P}/T)$ 



## PG-TO247-3



DBM	MILLIM	ETERS	INCHES		
Daw	MIN	MAX	MIN	MAX	
A	4,83	5.21	0.190	0.205	
A1	2.27	2,54	0.089	0,100	
A2	1.85	2,16	0,073	0.085	
ь	1.07	1.33	0.042	0,052	
b1	1.90	2,41	0.075	0,095	
b2	1.90	2,16	0.075	0,085	
b3	2,87	3.38	0.113	0.133	
b4	2.87	3.13	0.113	0,123	
c	0.55	0.68	0.022	0.027	
D	20,80	21,10	0,819	0.831	
D1	16,25	17,65	0,640	0,695	
D2	0.95	1.35	0.037	0,053	
E	15.70	16,13	0.618	0,635	
E1	13.10	14.15	0.516	0,557	
E2	3.68	5.10	0.145	0,201	
E3	1,00	2.60	0.039	0,102	
e	5.	44 (BSC)	0.2	214 (BSC)	
N	3			3	
E	19,80	20,32	0.780	0,800	
L1	4.10	4.47	0.161	0.176	
øΡ	3,50	3.70	0.138	0,146	
Q	5,49	6,00	0.216	0,236	
S	6.04	6.30	0,238	0,248	

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